PQ15RW08/PQ15RW11/PQ15RW21

Variable Output, General Purpose Type Low Power-Loss Voltage Regulator

Features

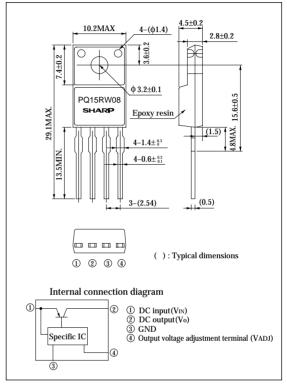
Low power-loss
 (Dropout voltage: MAX. 0.5V at Io=0.5A [PQ15RW08/11],
 Io=2A [PQ15RW21])

- Compact resin mold package (equivalent to TO-220)
- Variable output voltage (3.0 to 15V)
- Low voltage operation (Minimum supply voltage: 3.5V)
- Reference voltage precision: ±2.5%
- Built-in overcurrent, overheat protection functions, ASO protection circuit
- Lead forming type is also available.

Applications

 Power supplies for various electronic equipment such as AV, OA eguipment

Outline Dimensions (Unit : mm)



Absolute Maximum Ratings

(Ta=25°C)

Parameter	Symbol		T 1		
		PQ15RW08	PQ15RW11	PQ15RW21	Unit
*1 Input voltage	$V_{\rm IN}$		V		
*1 Output adjustment terminal voltage	Vadj		V		
Output current	Io	0.8	1.0	2.0	A
*2 Power dissipation	\mathbf{P}_{D1}	1.25	1	W	
	P_{D2}	10	15		W
*3 Junction temperature	Tj	150			°C
Operating temperature	Topr		°C		
Storage temperature	Tstg		°C		
Soldering temperature	Tsol		°C		

 $[\]ensuremath{^{\circledast 1}}$ All are open except GND and applicable terminals.

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^{#2} PD1: No heat sink, PD2: With infinite heat sink

^{*3} Overheat protection may operate at 125<=Tj<=150°C

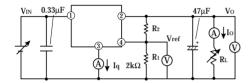
[·] Please refer to the chapter " Handling Precautions ".

Electrical Characteristics (Unless otherwise specified, conditions shall be V_{IN} =5V, V_0 =3.3V(R_1 =2kΩ, R_2 =500Ω), I_0 =0.5A) (T_a =25°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input voltage	Vin		3.5	_	20	V
Output voltage	Vo		3.0	_	15	V
Load regulation	RegL	*4	_	0.3	2.0	%
Line regulation	RegI	V _{IN} =5 to 15V, Io=5mA	I	0.5	2.5	%
Ripple rejection	RR	Refer to Fig. 2	45	55		dB
Reference voltage	V_{ref}		2.574	2.64	2.706	V
Temperature coefficient of reference voltage	TcVref	Tj=0 to 125°C	ı	±0.01	_	%/°C
Dropout voltage	V _{i-o}	V _{IN} =3.5V, *5	I	I	0.5	V
Quiescent current	I_q	Io=0A			8	mA

^{*4} PQ15RW08: Io=5mA to 0.8A, PQ15RW11: Io=5mA to 1A, PQ15RW21: Io=5mA to 2A

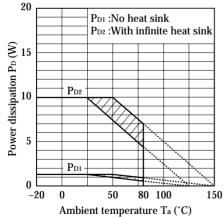
Fig. 1 Test Circuit



$$Vo=Vref\,x\left(1+\frac{-R_2}{-R_1}\right)Nearly=2.64\,x\left(1+\frac{-R_2}{-R_1}\right)$$

$$[R_1=2k\Omega,Vref\ Nearly=2.64V]$$

Fig. 3 Power Dissipation vs. Ambient Temperature (PQ15RW08)



Note) Oblique line portion: Overheat protection may operate in this area.

Fig. 2 Test Circuit of Ripple Rejection

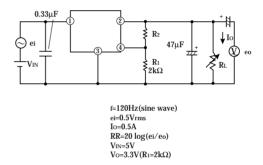
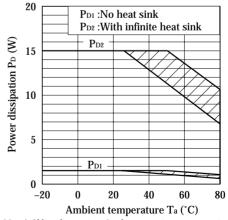


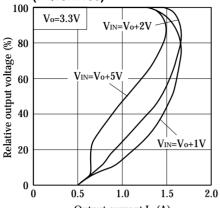
Fig. 4 Power Dissipation vs. Ambient Temperature(PQ15RW11/21)



Note) Oblique line portion: Overheat protection may operate in this area.

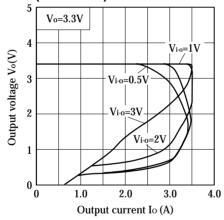
^{*5} PQ15RW08/PQ15RW11: Io=0.5A, PQ15RW21: Io=2A

Fig. 5 Overcurrent Protection Characteristics (Typical Value) (PQ15RW08)



Output current Io (A)

Fig. 7 Overcurrent Protection
Characteristics (Typical Value)
(PQ15RW21)



Typical Application

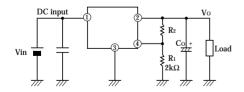
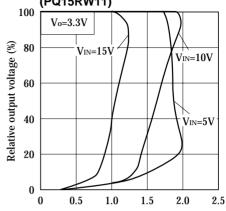
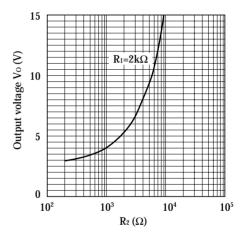


Fig. 6 Overcurrent Protection Characteristics (Typical Value) (PQ15RW11)



Output current Io (A)

Fig. 8 Output Voltage Adjustment
Characteristics



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